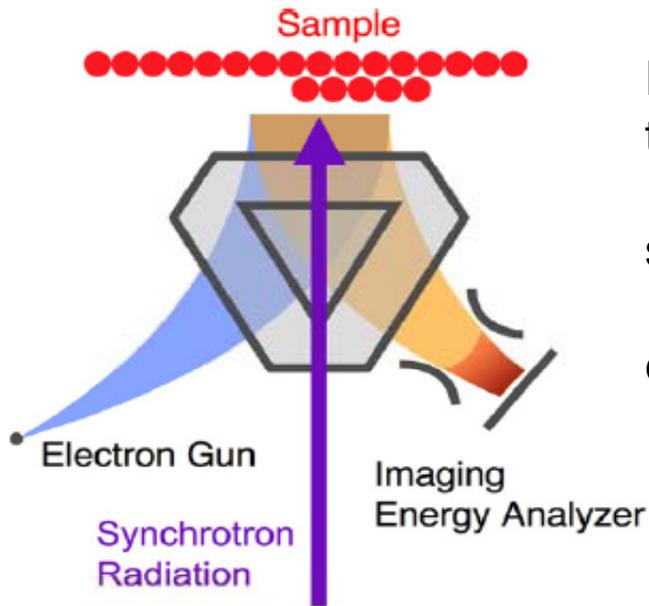


Photoemission Electron Microscopy/ Low-Energy Electron Microscopy (PEEM/LEEM)

U5UA



Full-field imaging with energy filtering in PEEM (2-100 μm)
topographic imaging, micro-LEED

spatial resolution 30-50 nm in PEEM
 5-10 nm in LEEM
energy resolution 0.2 eV

Science for PES
is still valid with the
addition of the spatial
resolution

extrinsic effects

- inhomogeneities
- patterning
- vicinal surfaces

intrinsic effects

- structural patterns
- magn. domains
- charge patterns
- chemical clocks